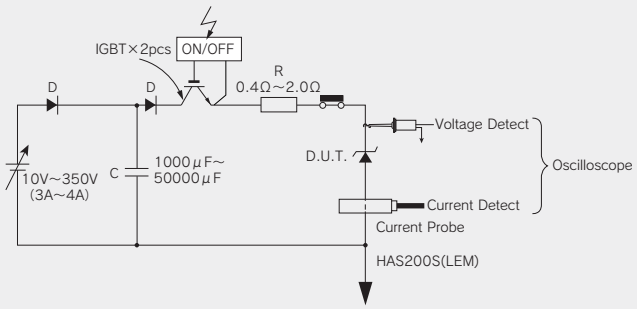
BACK-END ZENER DIODE

PRSM TEST SYSTEM PRSMテストシステム

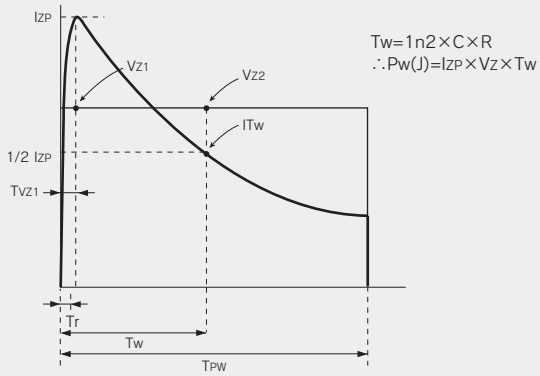
PRSM430Z 350V 300A

NEW

Fundamental Test Circuit



Test Timing



●PRSM430Z has been designed to measure clamp tolerance of zener diode by triangular wave forcing method (JEITA ED-4511B 4.2.5).

●本システムはツェナーダイオードのクランプ耐量を三角波印加法（JEITA ED-4511B 4.2.5）を用いて測定するシステムです。

MODEL	PRSM430Z
MEASURABLE DEVICES	ZENER DIODE
VD VOLTAGE	000V~350V
VZ2 VOLTAGE	00.0V~99.9V
IZP CURRENT	000A~300A
1/2 IZP TIME	00.00ms~99.99ms
VZ1 VOLTAGE	00.0V~99.9V
SETTING RANGE	
VD VOLTAGE	10V~350V(1V STEP)
CAPACITOR	1000μF~50000μF(1000μF STEP)
CURRENT LIMIT RESISTOR	0.4Ω~2.0Ω(0.1Ω STEP)
MAXIMUM CURRENT LIMIT	10A~300A(1A STEP)
FORCING TIME	1.0ms~99.9ms(0.1ms STEP)
VZ1 DETECT TIME	10μs~99μs
LOWER GATE/UPPER GATE	1.0V~99.9V
DIMENSIONS & WEIGHT	
MAIN UNIT	560(W)×1060(D)×1700(H)…340kg